



**12500 TI Boulevard, MS 8640, Dallas, Texas 75243**

**PCN# 20130326000**  
**Transfer of select devices in the .35um-UMC-F8J process**  
**to UMC-F8E Wafer Fab Facility**  
**Change Notification / Sample Request**

**Date:** 3/28/2013  
**To:** MOUSER PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager ([PCN\\_ww\\_admin\\_team@list.ti.com](mailto:PCN_ww_admin_team@list.ti.com)).

PCN Team  
SC Business Services  
Phone: +1(214) 480-6037  
Fax: +1(214) 480-6659




**20130326000**  
**Attachment: 1**

**Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

<b>DEVICE</b>	<b>CUSTOMER PART NUMBER</b>
PCM1606E	null
PCM1606EG4	null
PCM1742E	null
PCM1742EG4	null
PCM1742KE	null
PCM1748E	null
PCM1748KE	null
PCM1753DBQ	null
PCM1754DBQ	null
PCM1754DBQG4	null
PCM1754DBQR	null
PCM1755DBQ	null

Technical details of this Product Change follow on the next page(s).

<b>PCN Number:</b>	PCN20130326000			<b>PCN Date:</b>	03/28/2013
<b>Title:</b>	Transfer of select devices in the .35um-UMC-F8J process to UMC-F8E Wafer Fab Facility				
<b>Customer Contact:</b>	<a href="#">PCN Manager</a>	<b>Phone:</b>	+1(214)480-6037	<b>Dept:</b>	Quality Services
<b>Proposed 1<sup>st</sup> Ship Date:</b>	06/28/2013	<b>Estimated Sample Availability:</b>	Date provided at sample request.		
<b>Change Type:</b>					
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Assembly Materials
<input type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process
<input checked="" type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials	<input checked="" type="checkbox"/>	Wafer Fab Process
<b>PCN Details</b>					
<b>Description of Change:</b>					
This notification is to announce the transfer of select devices in the .35um-UMC-F8J process to UMC-F8E Wafer Fab Facility.					
Currently Qualified Sites, process, wafer dia.			Additional Sites, process, wafer dia.		
UMC-F8J, .35um-UMC-F8J Process, 200mm			UMC-F8E, 0.35 DPQM Process, 200mm		
<b>Reason for Change:</b>					
Continuity of supply due to site shutdown					
<b>Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):</b>					
None					
<b>Changes to product identification resulting from this PCN:</b>					
<b>Current</b>					
Chip Site	Chip site code (20L)	Chip country code (21L)			
UMC-F8J	U8J	JPN			
<b>New</b>					
Chip Site	Chip site code (20L)	Chip country code (21L)			
UMC-F8E	U8E	TWN			
Sample product shipping label (not actual product label)					
 MADE IN: Malaysia 2DC: 20: MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: 39 LBL: 5A (L)T0:1750		 	(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483S12 (P) (2P) REV: (V) 0033517 (20L) CS0: SHE (21L) CCO:USA (22L) AS0:MLA (23L) AS0:MYS		

Product Affected:			
PCM1606E	PCM1742EG4	PCM1748KE/2KG4	PCM1754DBQG4
PCM1606E/2K	PCM1742KE	PCM1748KEG4	PCM1754DBQR
PCM1606E/2KG4	PCM1742KE/2K	PCM1753DBQ	PCM1754DBQRG4
PCM1606EG	PCM1742KE/2KG4	PCM1753DBQG4	PCM1755DBQ
PCM1606EG/2K	PCM1742KEG4	PCM1753DBQR	PCM1755DBQG4
PCM1606EG/2KE6	PCM1748E	PCM1753DBQR-S2	PCM1755DBQR
PCM1606EG4	PCM1748E/2K	PCM1753DBQR-S2G4	PCM1755DBQR/2354
PCM1606EGE6	PCM1748E/2KG4	PCM1753DBQRG4	PCM1755DBQRG4
PCM1742E	PCM1748EG4	PCM1754DBQ	
PCM1742E/2K	PCM1748KE	PCM1754DBQ-P	
PCM1742E/2KG4	PCM1748KE/2K	PCM1754DBO-PG4	

Qualification Plan:					
This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.					
Qualification Device 1: PCM1753TDBQRQ1					
Wafer Fab Site:		UMC-F8E		Wafer Fab Process: 0.35 DPTM	
Wafer Diameter:		200mm			
Qualification Schedule:		Start:	03/2013	End:	End of 06/2013
Qualification: <input checked="" type="checkbox"/> Plan <input type="checkbox"/> Test Results					
Reliability Test		Conditions		Sample Size/Fails Lot#1 Lot#2 Lot#3	
High Temp Operating Life		140C(480 Hrs)		77/0	77/0 77/0
Electrical Characterization		-		Comp	Comp Comp
**High Temp Storage Bake		170C (420 Hrs)		77/0	77/0 77/0
**Biased HAST		130C/85%RH (96 Hrs)		77/0	77/0 77/0
**Autoclave		121C, 2 atm (96 Hrs)		77/0	77/0 77/0
**Temp Cycle		-65C/+150C (500 Cycles)		77/0	77/0 77/0
ESD CDM		250V		3/0	3/0 3/0
ESD HBM		1000V		3/0	3/0 3/0
Ball Bond Shear		76 balls, 3 units min		76/0	76/0 76/0
Bond Pull		76 Wire, 3 units min		76/0	76/0 76/0
Die Shear		-		10/0	10/0 10/0
Latch-up		(Per JESD78)		6/0	6/0 6/0
** Preconditioning sequence: (Level 3/260C)					

Qualification Device 2: PCM3168ATPAPRQ1					
Wafer Fab Site:		UMC-F8E	Wafer Fab Process:		0.35 DPTM
Wafer Diameter:		200mm			
Qualification: <input checked="" type="checkbox"/> Plan <input type="checkbox"/> Test Results					
Reliability Test		Conditions	Sample Size/Fails		
			Lot#1	Lot#2	Lot#3
High Temp Operating Life		125C(1000 Hrs)	77/0	77/0	77/0
Electrical Characterization		-	Comp	Comp	Comp
**High Temp. Storage Life		150C(1000Hrs)	77/0	77/0	77/0
**Biased HAST		130C/85%RH (96 Hrs)	77/0	77/0	77/0
**Autoclave		121C, 2 atm (96 Hrs)	77/0	77/0	77/0
**Temp Cycle		-65C/+150C (500 Cycles)	77/0	77/0	77/0
ESD CDM		250V	3/0	3/0	3/0
ESD HBM		1000V	3/0	3/0	3/0
Ball Bond Shear		76 balls, 3 units min	76/0	76/0	76/0
Bond Pull		76 Wire, 3 units min	76/0	76/0	76/0
Die Shear		-	10/0	10/6	10/0
Latch-up		(Per JESD78)	6/0	6/0	6/0
** Preconditioning sequence: (Level 3/260C)					

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	<a href="mailto:PCNAmericasContact@list.ti.com">PCNAmericasContact@list.ti.com</a>
Europe	<a href="mailto:PCNEuropeContact@list.ti.com">PCNEuropeContact@list.ti.com</a>
Asia Pacific	<a href="mailto:PCNAsiaContact@list.ti.com">PCNAsiaContact@list.ti.com</a>
Japan	<a href="mailto:PCNJapanContact@list.ti.com">PCNJapanContact@list.ti.com</a>